

Notice of References Cited	Application/Control No. 10/022,622	Applicant(s)/Patent Under Reexamination KIM, KI-TAEK	
	Examiner Feben M. Haile	Art Unit 2616	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,975,651	12-2005	Ono et al.	370/474
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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